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What is "Embedded - Microcontrollers"?

"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Active
Core Processor	e200z0h
Core Size	32-Bit Single-Core
Speed	64MHz
Connectivity	CANbus, LINbus, SPI, UART/USART
Peripherals	DMA, POR, PWM, WDT
Number of I/O	49
Program Memory Size	768KB (768K x 8)
Program Memory Type	FLASH
EEPROM Size	64K x 8
RAM Size	64K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 3.6V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 105°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP
Supplier Device Package	100-LQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/spc56ap54l3befbr

Table 1. Device summary

Package	Part number	
	768 KB Flash	1 MB Flash
LQFP144	SPC560P54L5 SPC56AP54L5	SPC560P60L5 SPC56AP60L5
LQFP100	SPC560P54L3 SPC56AP54L3	SPC560P60L3 SPC56AP60L3

1 Introduction

1.1 Document overview

This document provides electrical specifications, pin assignments, and package diagrams for the SPC56xP54x/SPC56xP60x series of microcontroller units (MCUs). It also describes the device features and highlights important electrical and physical characteristics. For functional characteristics, refer to the device reference manual.

1.2 Description

This 32-bit system-on-chip (SoC) automotive microcontroller family is the latest achievement in integrated automotive application controllers. It belongs to an expanding range of automotive-focused products designed to address chassis applications specifically the airbag application.

This family is one of a series of next-generation integrated automotive microcontrollers based on the Power Architecture technology.

The advanced and cost-efficient host processor core of this automotive controller family complies with the Power Architecture embedded category. It operates up to 64 MHz and offers high performance processing optimized for low power consumption. It capitalizes on the available development infrastructure of current Power Architecture devices and is supported with software drivers, operating systems and configuration code to assist with users implementations.

1.3 Device comparison

Table 2 provides a summary of different members of the SPC56xP54x/SPC56xP60x family and their features—relative to Full-featured version—to enable a comparison among the family members and an understanding of the range of functionality offered within this family.

Table 2. SPC56xP54x/SPC56xP60x device comparison

Feature	SPC560P54	SPC560P60	SPC56AP54	SPC56AP60
Code Flash memory (with ECC)	768 KB	1 MB	768 KB	1 MB
Data Flash / EE (with ECC)	64 KB			
SRAM (with ECC)	64 KB	80 KB	64 KB	80 KB
Processor core	32-bit e200z0h		32-bit Dual e200z0h	
Instruction set	VLE			
CPU performance	0-64 MHz			
FMPLL (frequency-modulated phase-locked loop) modules	1			
INTC (interrupt controller) channels	148			
PIT (periodic interrupt timer)	1 (includes four 32-bit timers)			

Table 4. SPC56xP54x/SPC56xP60x series block summary

Block	Function
Analog-to-digital converter (ADC)	Multi-channel, 10-bit analog-to-digital converter
Boot assist module (BAM)	Block of read-only memory containing VLE code which is executed according to the boot mode of the device
Clock generation module (MC_CGM)	Provides logic and control required for the generation of system and peripheral clocks
Controller area network (FlexCAN)	Supports the standard CAN communications protocol
Cross triggering unit (CTU)	Enables synchronization of ADC conversions with a timer event from the eMIOS or from the PIT
Crossbar switch (XBAR)	Supports simultaneous connections between two master ports and three slave ports. The crossbar supports a 32-bit address bus width and a 32-bit data bus width.
Cyclic redundancy checker (CRC) unit	Is dedicated to the computation of CRC off-loading the CPU. Each context has a separate CRC computation engine in order to allow the concurrent computation of the CRC of multiple data streams.
Deserial serial peripheral interface (DSPI)	Provides a synchronous serial interface for communication with external devices
Enhanced direct memory access (eDMA)	Performs complex data transfers with minimal intervention from a host processor via “*n*” programmable channels
Enhanced timer (eTimer)	Provides enhanced programmable up/down modulo counting
Error correction status module (ECSM)	Provides a myriad of miscellaneous control functions for the device including program-visible information about configuration and revision levels, a reset status register, wakeup control for exiting sleep modes, and optional features such as information on memory errors reported by error-correcting codes
External oscillator (XOSC)	Provides an output clock used as input reference for FMPLL_0 or as reference clock for specific modules depending on system needs
Fault collection and control unit (FCCU)	Provides functional safety to the device
Flash memory	Provides non-volatile storage for program code, constants and variables
FlexRay (FlexRay communication controller)	Provides high-speed distributed control for advanced automotive applications
Frequency-modulated phase-locked loop (FMPLL)	Generates high-speed system clocks and supports programmable frequency modulation
Interrupt controller (INTC)	Provides priority-based preemptive scheduling of interrupt requests
JTAG controller	Provides the means to test chip functionality and connectivity while remaining transparent to system logic when not in test mode
LINFlex controller	Manages a high number of LIN (Local Interconnect Network protocol) messages efficiently with a minimum of CPU load
Mode entry module (MC_ME)	Provides a mechanism for controlling the device operational mode and mode transition sequences in all functional states; also manages the power control unit, reset generation module and clock generation module, and holds the configuration, control and status registers accessible for applications

Table 4. SPC56xP54x/SPC56xP60x series block summary (continued)

Block	Function
Peripheral bridge (PBRIDGE)	Is the interface between the system bus and on-chip peripherals
Periodic interrupt timer (PIT)	Produces periodic interrupts and triggers
Power control unit (MC_PCU)	Reduces the overall power consumption by disconnecting parts of the device from the power supply via a power switching device; device components are grouped into sections called “power domains” which are controlled by the PCU
Reset generation module (MC_RGM)	Centralizes reset sources and manages the device reset sequence of the device
Semaphore unit (SEMA4)	Provides the hardware support needed in multi-core systems for implementing semaphores and provide a simple mechanism to achieve lock/unlock operations via a single write access
Static random-access memory (SRAM)	Provides storage for program code, constants, and variables
System integration unit lite (SIUL)	Provides control over all the electrical pad controls and up 32 ports with 16 bits of bidirectional, general-purpose input and output signals and supports up to 32 external interrupts with trigger event configuration
System status and configuration module (SSCM)	Provides system configuration and status data (such as memory size and status, device mode and security status), device identification data, debug status port enable and selection, and bus and peripheral abort enable/disable
System timer module (STM)	Provides a set of output compare events to support AUTOSAR(1) and operating system tasks
System watchdog timer (SWT)	Provides protection from runaway code
Wakeup unit (WKPU)	Supports up to 18 external sources that can generate interrupts or wakeup events, of which 1 can cause non-maskable interrupt requests or wakeup events.

1. AUTOSAR: AUTomotive Open System ARchitecture (see autosar.org web site).

1.5 Feature details

1.5.1 High performance e200z0h core processor

The e200z0h Power Architecture core provides the following features:

- High performance e200z0 core processor for managing peripherals and interrupts
- Single issue 4-stage pipeline in-order execution 32-bit Power Architecture CPU
- Harvard architecture
- Variable length encoding (VLE), allowing mixed 16-bit and 32-bit instructions
  - Results in smaller code size footprint
  - Minimizes impact on performance
- Branch processing acceleration using lookahead instruction buffer
- Load/store unit
  - 1-cycle load latency
  - Misaligned access support
  - No load-to-use pipeline bubbles
- Thirty-two 32-bit general purpose registers (GPRs)
- Separate instruction bus and load/store bus Harvard architecture
- Hardware vectored interrupt support
- Reservation instructions for implementing read-modify-write constructs
- Long cycle time instructions, except for guarded loads, do not increase interrupt latency
- Extensive system development support through Nexus debug port
- Non maskable Interrupt support

1.5.2 Crossbar switch (XBAR)

The XBAR multi-port crossbar switch supports simultaneous connections between six master ports and six slave ports. The crossbar supports a 32-bit address bus width and a 32-bit data bus width.

The crossbar allows for two concurrent transactions to occur from any master port to any slave port; but one of those transfers must be an instruction fetch from internal flash memory. If a slave port is simultaneously requested by more than one master port, arbitration logic selects the higher priority master and grant it ownership of the slave port. All other masters requesting that slave port are stalled until the higher priority master completes its transactions. Requesting masters are treated with equal priority and will be granted access to a slave port in round-robin fashion, based upon the ID of the last master to be granted access.

The crossbar provides the following features:

- 6 master ports:
  - 2 e200z0 core complex Instruction ports
  - 2 e200z0 core complex Load/Store Data ports
  - eDMA
  - FlexRay
- 6 slave ports:
  - 2 Flash memory (code flash and data flash)
  - 2 SRAM (48 KB + 32 KB)
  - 2 PBRIDGE
- 32-bit internal address, 32-bit internal data paths
- Fixed Priority Arbitration based on Port Master
- Temporary dynamic priority elevation of masters

1.5.3 Enhanced direct memory access (eDMA)

The enhanced direct memory access (eDMA) controller is a second-generation module capable of performing complex data movements via 16 programmable channels, with minimal intervention from the host processor. The hardware micro architecture includes a DMA engine which performs source and destination address calculations, and the actual data movement operations, along with an SRAM-based memory containing the transfer control descriptors (TCD) for the channels. This implementation is utilized to minimize the overall block size.

The eDMA module provides the following features:

- 16 channels support independent 8, 16 or 32-bit single value or block transfers
- Supports variable sized queues and circular queues
- Source and destination address registers are independently configured to post-increment or remain constant
- Each transfer is initiated by a peripheral, CPU, or eDMA channel request
- Each eDMA channel can optionally send an interrupt request to the CPU on completion of a single value or block transfer
- DMA transfers possible between system memories, DSPIs, ADC, eTimer and CTU
- Programmable DMA Channel Multiplexer for assignment of any DMA source to any available DMA channel with up to 30 potential request sources
- eDMA abort operation through software

1.5.4 On-chip flash memory with ECC

The SPC56xP54x/SPC56xP60x provides up to 1024 KB of programmable, non-volatile, flash memory. The non-volatile memory (NVM) can be used for instruction and/or data storage. The flash memory module interfaces the system bus to a dedicated flash memory array controller. It supports a 32-bit data bus width at the system bus port, and a 128-bit read data interface to flash memory. The module contains a four-entry, 4x128-bit prefetch buffers. Prefetch buffer hits allow no-wait responses. Normal flash memory array accesses are registered and are forwarded to the system bus on the following cycle, incurring 2 wait states.

1.5.21 Serial communication interface module (LINFlex)

The LINFlex on the SPC56xP54x/SPC56xP60x features the following:

- Supports LIN Master mode (on both modules), LIN Slave mode (on one module) and UART mode
- LIN state machine compliant to LIN1.3, 2.0, and 2.1 Specifications
- Handles LIN frame transmission and reception without CPU intervention
- LIN features
  - Autonomous LIN frame handling
  - Message buffer to store Identifier and up to 8 data bytes
  - Supports message length as long as 64 bytes
  - Detection and flagging of LIN errors: Sync field; Delimiter; ID parity; Bit; Framing; Checksum and Time-out errors
  - Classic or extended checksum calculation
  - Configurable Break duration as long as 36-bit times
  - Programmable Baud rate prescalers (13-bit mantissa, 4-bit fractional)
  - Diagnostic features: Loop back; Self Test; LIN bus stuck dominant detection
  - Interrupt-driven operation with 16 interrupt sources
- LIN slave mode features
  - Autonomous LIN header handling
  - Autonomous LIN response handling
- UART mode
  - Full-duplex operation
  - Standard non return-to-zero (NRZ) mark/space format
  - Data buffers with 4-byte receive, 4-byte transmit
  - Configurable word length (8-bit or 9-bit words)
  - Error detection and flagging
  - Parity, Noise and Framing errors
  - Interrupt-driven operation with four interrupt sources
  - Separate transmitter and receiver CPU interrupt sources
  - 16-bit programmable baud-rate modulus counter and 16-bit fractional
  - 2 receiver wake-up methods

1.5.22 Deserial serial peripheral interface (DSPI)

The deserial serial peripheral interface (DSPI) module provides a synchronous serial interface for communication between the SPC56xP54x/SPC56xP60x MCU and external devices.

- Watchpoint triggering, watchpoint triggers program tracing
- DDR

- Auxiliary Output Port
  - 4 MDO (Message Data Out) pins
  - MCKO (Message Clock Out) pin
  - 2 $\overline{\text{MSEO}}$ (Message Start/End Out) pins
  - $\overline{\text{EVTO}}$ (Event Out) pin
- Auxiliary Input Port
  - $\overline{\text{EVTI}}$ (Event In) pin[a]

1.5.28 IEEE 1149.1 (JTAG) controller

The JTAG controller (JTAGC) block provides the means to test chip functionality and connectivity while remaining transparent to system logic when not in test mode. All data input to and output from the JTAGC block is communicated in serial format. The JTAGC block is compliant with the IEEE standard.

The JTAG controller provides the following features:

- IEEE Test Access Port (TAP) interface with four pins (TDI, TMS, TCK, TDO)
- Selectable modes of operation include JTAGC/debug or normal system operation.
- A 5-bit instruction register that supports the following IEEE 1149.1-2001 defined instructions:
  - BYPASS, IDCODE, EXTEST, SAMPLE, SAMPLE/PRELOAD
- A 5-bit instruction register that supports the additional following public instructions:
  - ACCESS_AUX_TAP_NPC, ACCESS_AUX_TAP_CORE0, ACCESS_AUX_TAP_CORE1, ACCESS_AUX_TAP_NASPS_0, ACCESS_AUX_TAP_NASPS_1
- Three test data registers: a bypass register, a boundary scan register, and a device identification register.
- A TAP controller state machine that controls the operation of the data registers, instruction register and associated circuitry.

1.5.29 On-chip voltage regulator (VREG)

The on-chip voltage regulator module provides the following features:

- Uses external NPN transistor
- Regulates external 3.3 V to 5.0 V down to 1.2 V for the core logic
- Low voltage detection on the internal 1.2 V and I/O voltage 3.3 V

a. At least one TCK clock is necessary for the EVTI signal to be recognized by the MCU.

Table 5. Supply pins (continued)

Supply		Pin		
Symbol	Description	LQFP 100	LQFP 144	LQFP 176[1]
$V_{DD\_HV\_REG}$ (3.3 V or 5.0 V)	Voltage regulator supply voltage	50	72	86
$V_{DD\_LV\_REGCOR}$	1.2 V decoupling[2] pins for core logic supply and voltage regulator feedback. Decoupling capacitor must be connected between this pins and $V_{SS\_LV\_REGCOR}$.	48	70	82
$V_{SS\_LV\_REGCOR}$	1.2 V decoupling[2] pins for core logic GND and voltage regulator feedback. Decoupling capacitor must be connected between this pins and $V_{DD\_LV\_REGCOR}$.	49	71	85
ADC0 reference and supply voltage				
$V_{DD\_HV\_AD}$	ADC supply and high reference voltage	39	56	64
$V_{SS\_HV\_AD}$	ADC ground and low reference voltage	40	57	65
Power supply pins (3.3 V or 5.0 V)				
$V_{DD\_HV\_IO0}$	Input/Output supply voltage	—	6	14
$V_{SS\_HV\_IO0}$	Input/Output ground	—	7	15
$V_{DD\_HV\_IO1}$	Input/Output supply voltage	13	21	29
$V_{SS\_HV\_IO1}$	Input/Output ground	14	22	30
$V_{DD\_HV\_IO2}$	Input/Output supply voltage	63	91	115
$V_{SS\_HV\_IO2}$	Input/Output ground	62	90	114
$V_{DD\_HV\_IO3}$	Input/Output supply voltage	87	126	150
$V_{SS\_HV\_IO3}$	Input/Output ground	88	127	151
$V_{DD\_HV\_IO4}$	Input/Output supply voltage	—	—	169
$V_{SS\_HV\_IO4}$	Input/Output ground	—	—	170
$V_{DD\_HV\_IO5}$	Input/Output supply voltage	—	—	5
$V_{SS\_HV\_IO5}$	Input/Output ground	—	—	6
$V_{DD\_HV\_IO6}$	Input/Output supply voltage	—	—	108
$V_{SS\_HV\_IO6}$	Input/Output ground	—	—	109
$V_{DD\_HV\_FL}$	Code and data flash supply voltage	69	97	121
$V_{SS\_HV\_FL}$	Code and data flash supply ground	68	96	120
$V_{DD\_HV\_OSC}$	Crystal oscillator amplifier supply voltage	16	27	35
$V_{SS\_HV\_OSC}$	Crystal oscillator amplifier ground	17	28	36
Power supply pins (1.2 V)				
$V_{DD\_LV\_COR0}$	1.2 V Decoupling pins for core logic supply. Decoupling capacitor must be connected between these pins and the nearest $V_{SS\_LV\_COR0}$ pin.	12	18	26

Table 7. Pin muxing[1] (continued)

Port pin	PCR No.	Alternate function[2], [3]	Functions	Peripheral [4]	I/O direction [5]	Pad speed[6] SRC = 0	Pad speed SRC = 1	Pin LQFP 100	Pin LQFP 144	Pin LQFP 176[7]
C[15]	PCR[47]	ALT0 ALT1 ALT2 ALT3 —	GPIO[47] CA_TR_EN ETC[0] — EXT_IN	SIUL FlexRay_0 eTimer_1 — CTU_0	I/O O I/O — I	Slow	Symmetric	85	124	148
Port D										
D[0]	PCR[48]	ALT0 ALT1 ALT2 ALT3	GPIO[48] CA_TX ETC[1] —	SIUL FlexRay_0 eTimer_1 —	I/O O I/O —	Slow	Symmetric	86	125	149
D[1]	PCR[49]	ALT0 ALT1 ALT2 ALT3 —	GPIO[49] CS4_1 ETC[2] EXT_TRG CA_RX	SIUL DSPI_1 eTimer_1 CTU_0 FlexRay_0	I/O O I/O O I	Slow	Medium	3	3	3
D[2]	PCR[50]	ALT0 ALT1 ALT2 ALT3 —	GPIO[50] CS5_1 ETC[3] — CB_RX	SIUL DSPI_1 eTimer_1 — FlexRay_0	I/O O I/O — I	Slow	Medium	97	140	168
D[3]	PCR[51]	ALT0 ALT1 ALT2 ALT3	GPIO[51] CB_TX ETC[4] —	SIUL FlexRay_0 eTimer_1 —	I/O O I/O —	Slow	Symmetric	89	128	152
D[4]	PCR[52]	ALT0 ALT1 ALT2 ALT3	GPIO[52] CB_TR_EN ETC[5] —	SIUL FlexRay_0 eTimer_1 —	I/O O I/O —	Slow	Symmetric	90	129	153
D[5]	PCR[53]	ALT0 ALT1 ALT2 ALT3	GPIO[53] CS3_0 — SOUT_3	SIUL DSPI_0 — DSPI_3	I/O O — O	Slow	Medium	22	33	41
D[6]	PCR[54]	ALT0 ALT1 ALT2 ALT3	GPIO[54] CS2_0 SCK_3 SOUT_4	SIUL DSPI_0 DSPI_3 DSPI_4	I/O O I/O O	Slow	Medium	23	34	42

Table 7. Pin muxing(1) (continued)

Port pin	PCR No.	Alternate function(2), (3)	Functions	Peripheral (4)	I/O direction (5)	Pad speed(6)		Pin		
						SRC = 0	SRC = 1	LQFP 100	LQFP 144	LQFP 176(7)
D[7]	PCR[55]	ALT0 ALT1 ALT2 ALT3 —	GPIO[55] CS3_1 — CS4_0 SIN_3	SIUL DSPI_1 — DSPI_0 DSPI_3	I/O O — O I	Slow	Medium	26	37	45
D[8]	PCR[56]	ALT0 ALT1 ALT2 ALT3	GPIO[56] CS2_1 RDY CS5_0	SIUL DSPI_1 nexus_0 DSPI_0	I/O O O O	Slow	Medium	21	32	40
D[9]	PCR[57]	ALT0 ALT1 ALT2 ALT3	GPIO[57] — TXD CS6_1	SIUL — LINFlex_1 DSPI_1	I/O — O O	Slow	Medium	15	26	34
D[10]	PCR[58]	ALT0 ALT1 ALT2 ALT3	GPIO[58] — CS0_3 —	SIUL — DSPI_3 —	I/O — I/O —	Slow	Medium	53	76	92
D[11]	PCR[59]	ALT0 ALT1 ALT2 ALT3	GPIO[59] — CS1_3 SCK_3	SIUL — DSPI_3 DSPI_3	I/O — O I/O	Slow	Medium	54	78	94
D[12]	PCR[60]	ALT0 ALT1 ALT2 ALT3 —	GPIO[60] — — CS7_1 RXD	SIUL — — DSPI_1 LINFlex_1	I/O — — O I	Slow	Medium	70	99	123
D[13]	PCR[61]	ALT0 ALT1 ALT2 ALT3	GPIO[61] — CS2_3 SOUT_3	SIUL — DSPI_3 DSPI_3	I/O — O O	Slow	Medium	67	95	119
D[14]	PCR[62]	ALT0 ALT1 ALT2 ALT3 —	GPIO[62] — CS3_3 — SIN_3	SIUL — DSPI_3 — DSPI_3	I/O — O — I	Slow	Medium	73	105	129
D[15]	PCR[63]	ALT0 ALT1 ALT2 ALT3 —	GPIO[63] — — — AN[20]	SIUL — — — ADC_0	Input Only	—	—	41	58	66

Table 13. Thermal characteristics for 100-pin LQFP

Symbol		Parameter	Conditions	Typical value	Unit
$R_{\theta JA}$	D	Thermal resistance junction-to-ambient, natural convection(1)	Single layer board—1s	47.3	°C/W
	D		Four layer board—2s2p	35.6	°C/W
$R_{\theta JB}$	D	Thermal resistance junction-to-board(2)	Four layer board—2s2p	19.1	°C/W
$R_{\theta JCtop}$	D	Thermal resistance junction-to-case (top)(3)	Single layer board—1s	9.1	°C/W
Ψ_{JB}	D	Junction-to-board, natural convection(4)	Operating conditions	19.1	°C/W
Ψ_{JC}	D	Junction-to-case, natural convection(5)	Operating conditions	1.1	°C/W

1. Junction-to-ambient thermal resistance determined per JEDEC JESD51-7. Thermal test board meets JEDEC specification for this package.
2. Junction-to-board thermal resistance determined per JEDEC JESD51-8. Thermal test board meets JEDEC specification for the specified package.
3. Junction-to-case at the top of the package determined using MIL-STD 883 Method 1012.1. The cold plate temperature is used for the case temperature. Reported value includes the thermal resistance of the interface layer.
4. Thermal characterization parameter indicating the temperature difference between the board and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written as Psi-JB.
5. Thermal characterization parameter indicating the temperature difference between the case and the junction temperature per JEDEC JESD51-2. When Greek letters are not available, the thermal characterization parameter is written as Psi-JC.

3.5.1 General notes for specifications at maximum junction temperature

An estimation of the chip junction temperature, T_J, can be obtained from *Equation 1*:

Equation 1 $\mathbf{T_J = T_A + (R_{\theta JA} \times P_D)}$

where:

T_A= ambient temperature for the package (^oC)

$R_{\theta JA}$= junction to ambient thermal resistance ($^oC/W$)

P_D= power dissipation in the package (W)

The junction to ambient thermal resistance is an industry standard value that provides a quick and easy estimation of thermal performance. Unfortunately, there are two values in common usage: the value determined on a single layer board and the value obtained on a board with two planes. For packages such as the PBGA, these values can be different by a factor of two. Which value is closer to the application depends on the power dissipated by other components on the board. The value obtained on a single layer board is appropriate for the tightly packed printed circuit board. The value obtained on the board with the internal planes is usually appropriate if the board has low power dissipation and the components are well separated.

When a heat sink is used, the thermal resistance is expressed in *Equation 2* as the sum of a junction to case thermal resistance and a case to ambient thermal resistance:

Equation 2 $\mathbf{R_{\theta JA} = R_{\theta JC} + R_{\theta CA}}$

where:

$R_{\theta JA}$ = junction to ambient thermal resistance (°C/W)

$R_{\theta JC}$= junction to case thermal resistance (°C/W)

$R_{\theta CA}$= case to ambient thermal resistance (°C/W)

Table 24. Peripherals supply current (5 V and 3.3 V)(1)

Symbol		Parameter	Conditions		Value		Unit
					Typ	Max	
$I_{DD\_HV(CAN)}$	T	CAN (FlexCAN) supply current on VDD_HV_REG	500 Kbyte/s	Total (static + dynamic) consumption: – FlexCAN in loop-back mode – XTAL@ 8 MHz used as CAN engine clock source – Message sending period is 580 µs	21.6 * f_{periph}	28.1* f_{periph}	µA
$I_{DD\_HV(SCI)}$	T	SCI (LINFlex) supply current on VDD_HV_REG	Total (static + dynamic) consumption: – LIN mode – Baudrate: 115.2 Kbyte/s		10.8 * f_{periph}	14.1 * f_{periph}	µA
$I_{DD\_HV(SPI)}$	T	SPI (DSPI) supply current on VDD_HV_REG	Ballast dynamic consumption (continuous communication): – Baudrate: 2 Mbit/s – Transmission every 8 µs – Frame: 16 bits		4.8 * f_{periph}	6.3 * f_{periph}	µA
$I_{DD\_HV(ADC)}$	T	ADC supply current on VDD_HV_REG	VDD = 5.5 V	Ballast dynamic consumption (continuous conversion)	120 * f_{periph}	156 * f_{periph}	µA
$I_{DD\_HV\_ADC(ADC)}$	T	ADC supply current on VDD_HV_ADC	VDD = 5.5 V	Analog dynamic consumption (continuous conversion)	0.005 * f_{periph} + 2.8	0.007 * f_{periph} + 3.4	mA
$I_{DD\_HV(eTimer)}$	T	eTimer supply current on VDD_HV_REG	PWM signals generation on all 1 channel @10kHz	Dynamic consumption does not change varying the frequency	1.8	2.4	mA
$I_{DD\_HV(FlexRay)}$	T	FlexRay supply current on VDD_HV_REG	Static consumption		4.2 * f_{periph}	5.5 * f_{periph}	µA

1. Operating conditions: f_{periph} = 8 MHz to 64 MHz

The filter at the input pins must be designed taking into account the dynamic characteristics of the input signal (bandwidth) and the equivalent input impedance of the ADC itself.

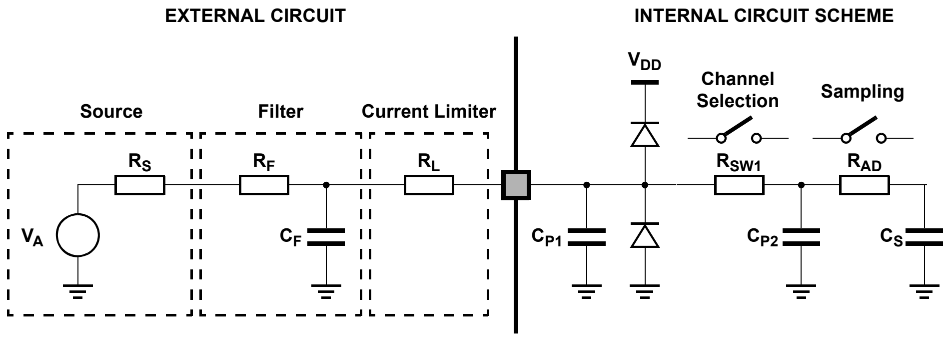
In fact a current sink contributor is represented by the charge sharing effects with the sampling capacitance: being C_S and C_{P2} substantially two switched capacitances, with a frequency equal to the ADC conversion rate, it can be seen as a resistive path to ground. For instance, assuming a conversion rate of 1 MHz, with $C_S + C_{P2}$ equal to 3 pF, a resistance of 330 kΩ is obtained ($R_{EQ} = 1 / (fc \times (C_S + C_{P2}))$, where fc represents the conversion rate at the considered channel). To minimize the error induced by the voltage partitioning between this resistance (sampled voltage on $C_S + C_{P2}$) and the sum of $R_S + R_F$, the external circuit must be designed to respect the *Equation 4*:

Equation 4

$$V_A \times \frac{R_S + R_F}{R_{EQ}} < \frac{1}{2} \mathrm{LSB}$$

Equation 4 generates a constraint for external network design, in particular on resistive path. Internal switch resistances (R_{SW} and R_{AD}) can be neglected with respect to external resistances.

Figure 16. Input equivalent circuit (precise channels)



R_S Source Impedance

R_F Filter Resistance

C_F Filter Capacitance

R_L Current Limiter Resistance

R_{SW1} Channel Selection Switch Impedance

R_{AD}Sampling Switch Impedance

C_P Pin Capacitance (two contributions, C_{P1} and C_{P2})

In particular two different transient periods can be distinguished:

- A first and quick charge transfer from the internal capacitance C_{P1} and C_{P2} to the sampling capacitance C_S occurs (C_S is supposed initially completely discharged): considering a worst case (since the time constant in reality would be faster) in which C_{P2} is reported in parallel to C_{P1} (call $C_P = C_{P1} + C_{P2}$), the two capacitances C_P and C_S are in series, and the time constant is

Equation 5

$$\tau_1 = (R_{SW} + R_{AD}) \times \frac{C_P \times C_S}{C_P + C_S}$$

Equation 5 can again be simplified considering only C_S as an additional worst condition. In reality, the transient is faster, but the A/D converter circuitry has been designed to be robust also in the very worst case: the sampling time T_S is always much longer than the internal time constant:

Equation 6

$$\tau_1 < (R_{SW} + R_{AD}) \times C_S \ll T_S$$

The charge of C_{P1} and C_{P2} is redistributed also on C_S, determining a new value of the voltage V_{A1} on the capacitance according to *Equation 7*:

Equation 7

$$V_{A1} \times (C_S + C_{P1} + C_{P2}) = V_A \times (C_{P1} + C_{P2})$$

- A second charge transfer involves also C_F (that is typically bigger than the on-chip capacitance) through the resistance R_L: again considering the worst case in which C_{P2} and C_S were in parallel to C_{P1} (since the time constant in reality would be faster), the time constant is:

Equation 8

$$\tau_2 < R_L \times (C_S + C_{P1} + C_{P2})$$

In this case, the time constant depends on the external circuit: in particular imposing that the transient is completed well before the end of sampling time T_S, a constraint on R_L sizing is obtained:

Equation 9

$$8.5 \times \tau_2 = 8.5 \times R_L \times (C_S + C_{P1} + C_{P2}) < T_S$$

Of course, R_L shall be sized also according to the current limitation constraints, in combination with R_S (source impedance) and R_F (filter resistance). Being C_F definitively bigger than C_{P1}, C_{P2} and C_S, then the final voltage V_{A2} (at the end of the charge transfer transient) will be much higher than V_{A1}. *Equation 10* must be respected (charge balance assuming now C_S already charged at V_{A1}):

Equation 10

$$V_{A2} \times (C_S + C_{P1} + C_{P2} + C_F) = V_A \times C_F + V_{A1} \times (C_{P1} + C_{P2} + C_S)$$

The two transients above are not influenced by the voltage source that, due to the presence of the R_FC_F filter, is not able to provide the extra charge to compensate the voltage drop on

Table 32. ADC conversion characteristics (continued)

Symbol		Parameter	Conditions(1)	Value			Unit
				Min	Typ	Max	
TUE	T	Total unadjusted error with current injection	16 precision channels	–3	—	3	LSB
TUE	T	Total unadjusted error with current injection	10 standard channels	–4	—	4	LSB

1. V_{DD} = 3.3 V to 3.6 V / 4.5 V to 5.5 V, T_A = –40 °C to $T_{A\ MAX}$, unless otherwise specified and analog input voltage from $V_{SS\_HV\_AD}$ to $V_{DD\_HV\_AD}$.
2. V_{INAN} may exceed V_{SS_ADC} and V_{DD_ADC} limits, remaining on absolute maximum ratings, but the results of the conversion will be clamped respectively to 0x000 or 0x3FF.
3. AD_clk clock is always half of the ADC module input clock defined via the auxiliary clock divider for the ADC.
4. When configured to allow 60 MHz ADC, the minimum ADC clock speed is 9 MHz, below which precision is lost.
5. During the sample time the input capacitance CS can be charged/discharged by the external source. The internal resistance of the analog source must allow the capacitance to reach its final voltage level within t_{ADC_S}. After the end of the sample time t_{ADC_S}, changes of the analog input voltage have no effect on the conversion result. Values for the sample clock t_{ADC_S} depend on programming.
6. This parameter includes the sample time t_{ADC_S}.
7. 20 MHz ADC clock. Specific prescaler is programmed on MC_PLL_CLK to provide 20 MHz clock to the ADC.
8. See *Figure 16*.

3.16 Flash memory electrical characteristics

Table 33. Program and erase specifications

Symbol		Parameter	Conditions	Value				Unit
				Min	Typ(1)	Initial max(2)	Max(3)	
$T_{wprogram}$	P	Word Program (32 bits) Time(4)	Data Flash	—	30	70	500	µs
$T_{dwprogram}$	P	Double Word (64 bits) Program Time(4)	Code Flash	—	18	50	500	µs
T_{BKPRG}	P	Bank Program (64 KB)(4), (5)	Data Flash	—	0.49	1.2	4.1	s
	P	Bank Program (1056 KB)(4), (5)	Code Flash	—	2.6	6.6	66	s
T_{MDPRG}	P	Module Program (512 KB)(4)	Code Flash	—	1.3	1.65	33	s
$T_{16kpperase}$	P	16 KB Block Pre-program and Erase Time	Code Flash	—	200	500	5000	ms
			Data Flash		700	800		
$T_{32kpperase}$	P	32 KB Block Pre-program and Erase Time	Code Flash	—	300	600	5000	ms
$T_{64kpperase}$	P	64 KB Block Pre-program and Erase Time	Code Flash	—	400	900	5000	ms
$T_{128kpperase}$	P	128 KB Block Pre-program and Erase Time	Code Flash	—	600	1300	5000	ms
t_{ESRT}	P	Erase Suspend Request Rate(6)	Code Flash	20	—	—	—	ms
			Data Flash	10				

1. Typical program and erase times assume nominal supply values and operation at 25 °C. All times are subject to change pending device characterization.
2. Initial factory condition: < 100 program/erase cycles, 25 °C, typical supply voltage.

Figure 20. Start-up reset requirements[g]

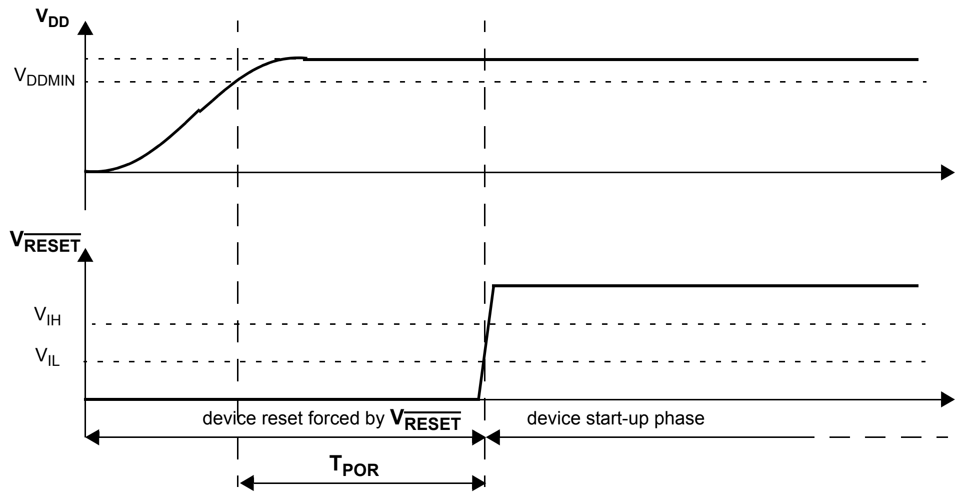
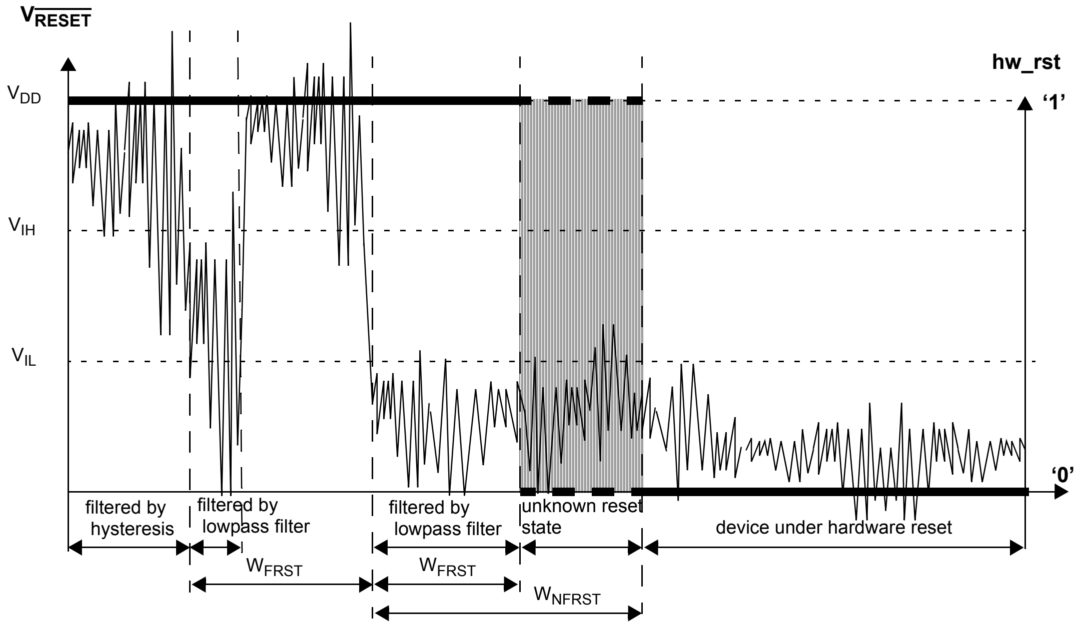


Figure 21. Noise filtering on reset signal



g. The output drive provided is open drain and hence must be terminated by an external resistor of value 1 kΩ.

Figure 23. JTAG test access port timing

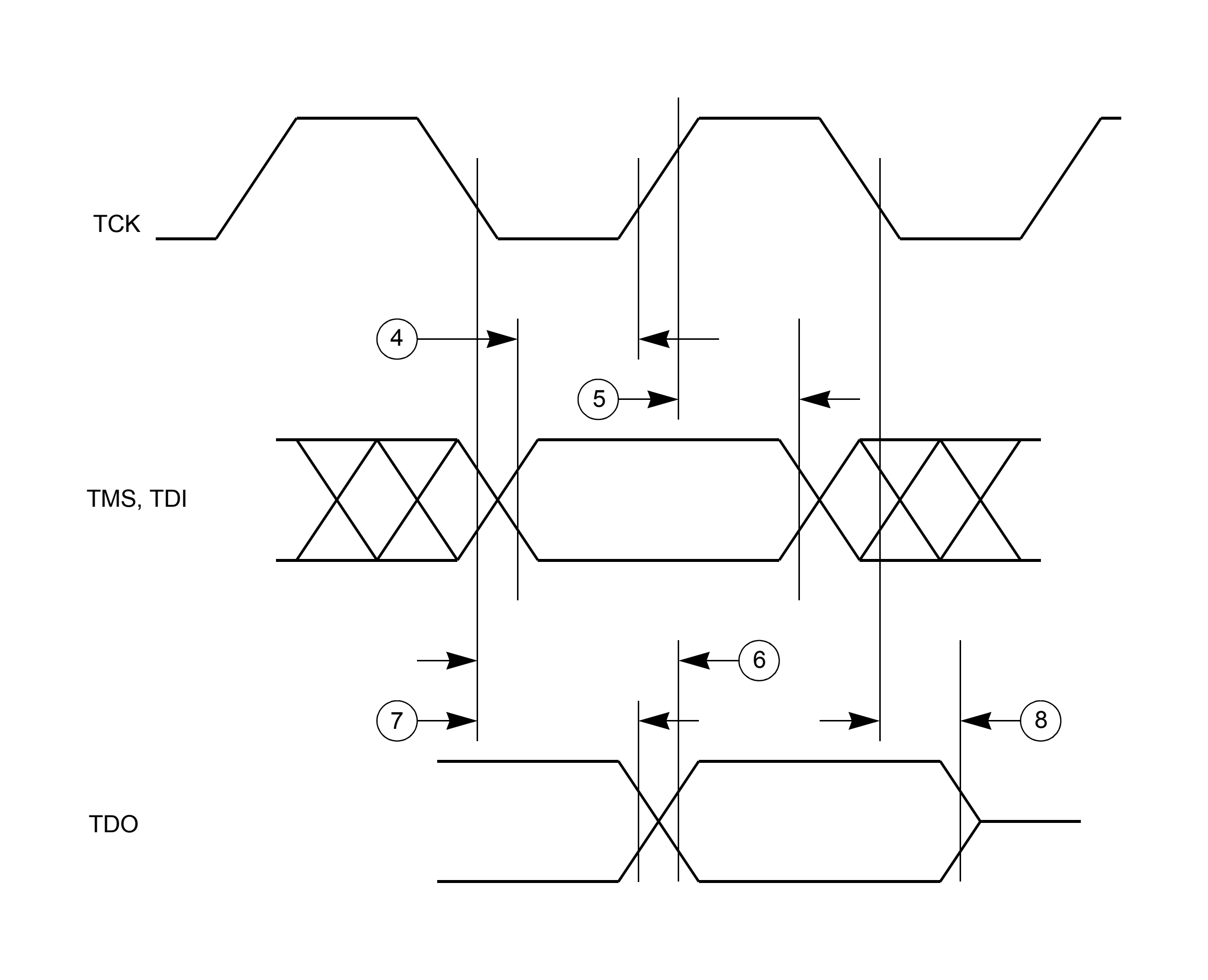
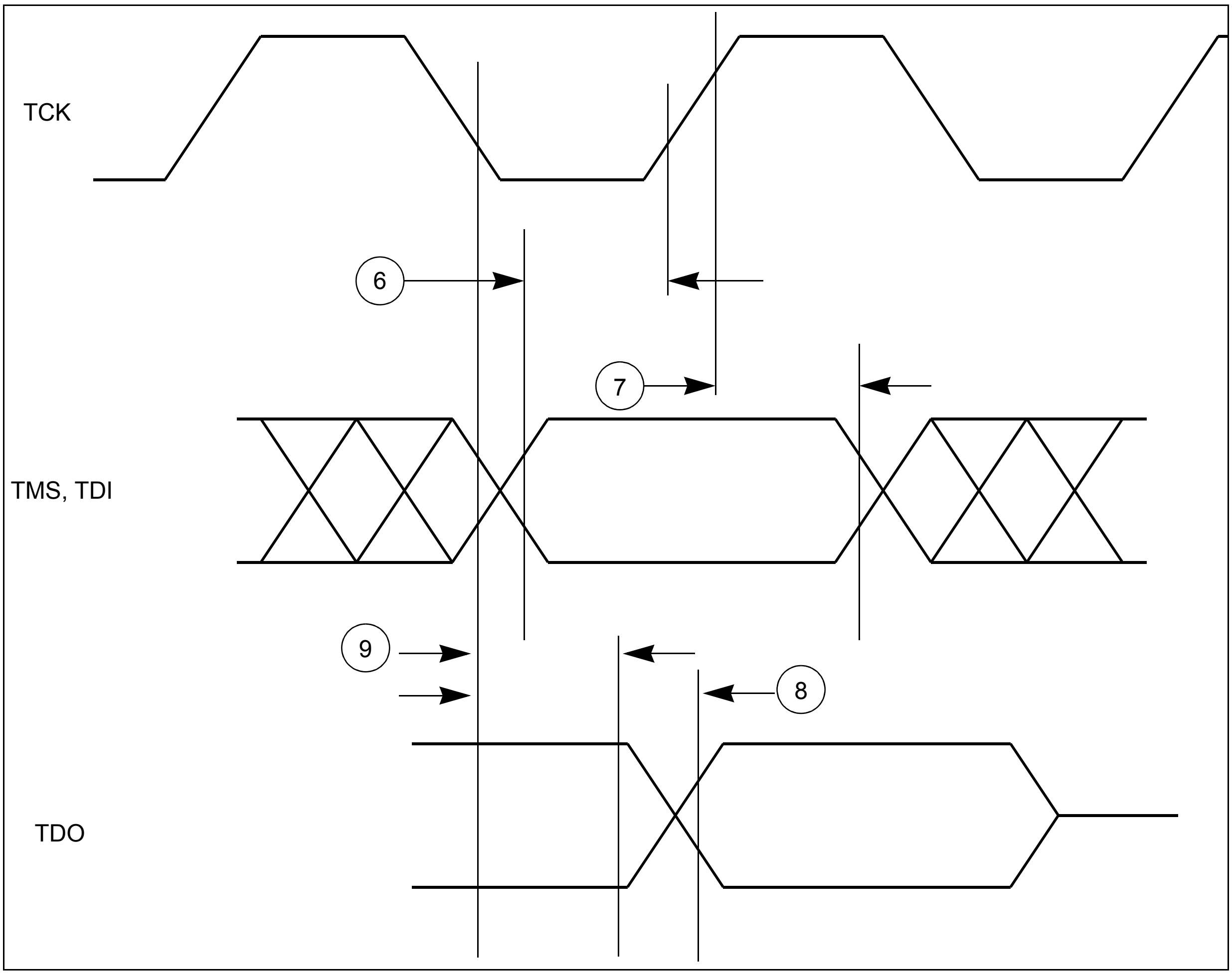


Figure 27. Nexus TDI, TMS, TDO timing



3.18.4 External interrupt timing (IRQ pin)

Table 40. External interrupt timing[1]

No.	Symbol		C	Parameter	Conditions	Min	Max	Unit
1	t_{IPWL}	CC	D	IRQ pulse width low	—	4	—	t_{CYC}
2	t_{IPWH}	CC	D	IRQ pulse width high	—	4	—	t_{CYC}
3	t_{ICYC}	CC	D	IRQ edge to edge time[2]	—	4 + N [3]	—	t_{CYC}

1. IRQ timing specified at f_{SYS} = 64 MHz and $V_{DD\_HV\_IOx}$ = 3.0 V to 5.5 V, $T_A = T_L$ to T_H, and CL = 200pF with SRC = 0b00.
2. Applies when IRQ pins are configured for rising edge or falling edge events, but not both.
3. N= ISR time to clear the flag.

4 Package characteristics

4.1 ECOPACK®

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: *www.st.com*. ECOPACK® is an ST trademark.

4.2 Package mechanical data

4.2.1 LQFP144 mechanical outline drawing

Figure 38. LQFP144 package mechanical drawing